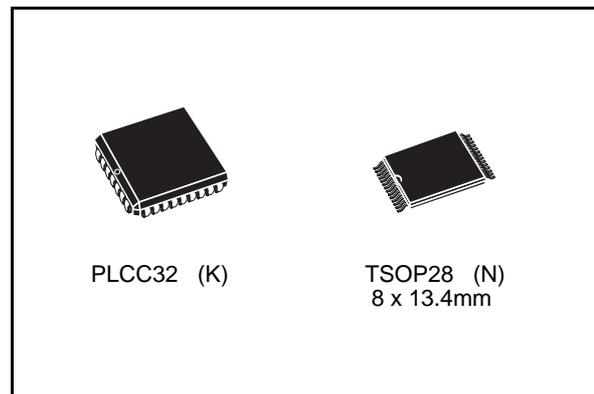




## 512 Kbit (64Kb x 8) Low Voltage OTP EPROM

- **LOW VOLTAGE READ OPERATION:**  
2.7V to 3.6V
- **FAST READ ACCESS TIME:**
  - 90ns at  $V_{CC} = 3.0V$  to 3.6V
  - 100ns at  $V_{CC} = 2.7V$  to 3.6V
- **PIN COMPATIBLE** with M27C512
- **LOW POWER CONSUMPTION:**
  - 15 $\mu$ A max Standby Current
  - 15mA max Active Current at 5MHz
- **PROGRAMMING TIME** 100 $\mu$ s/byte (typical)
- **HIGH RELIABILITY CMOS TECHNOLOGY**
  - 2,000V ESD Protection
  - 200mA Latchup Protection Immunity
- **ELECTRONIC SIGNATURE**
  - Manufacturer Code: 20h
  - Device Code: 3Dh



### DESCRIPTION

The M27W512 is a low voltage 512 Kbit EPROM offered in the OTP range (one time programmable). It is ideally suited for microprocessor systems and is organized as 65,536 by 8 bits.

The M27W512 operates in the read mode with a supply voltage as low as 2.7V at  $-40$  to  $85^{\circ}C$  temperature range. The decrease in operating power allows either a reduction of the size of the battery or an increase in the time between battery recharges.

The M27W512 is offered in PLCC32 and TSOP28 (8 x 13.4 mm) packages.

**Table 1. Signal Names**

A0-A15	Address Inputs
Q0-Q7	Data Outputs
$\bar{E}$	Chip Enable
$\bar{G}V_{PP}$	Output Enable / Program Supply
$V_{CC}$	Supply Voltage
$V_{SS}$	Ground

**Figure 1. Logic Diagram**

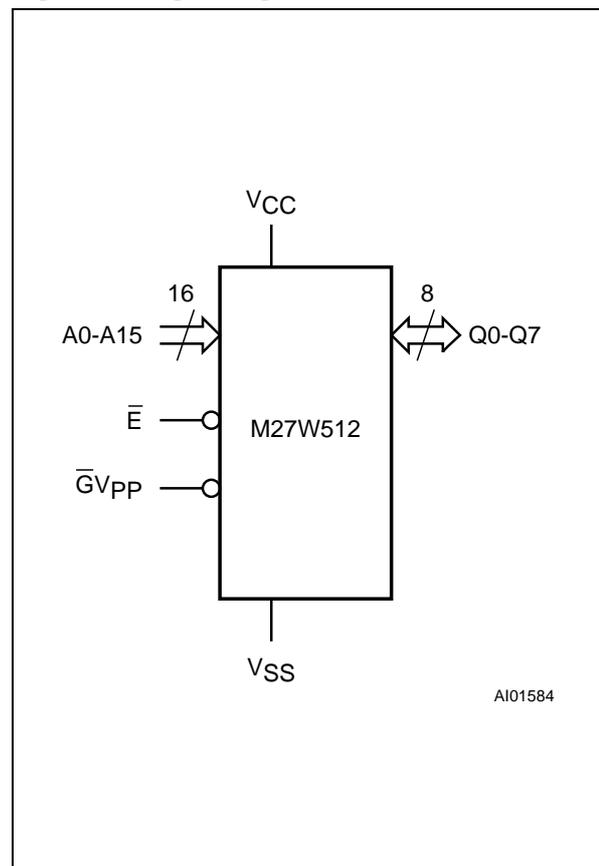


Figure 2A. LCC Pin Connections

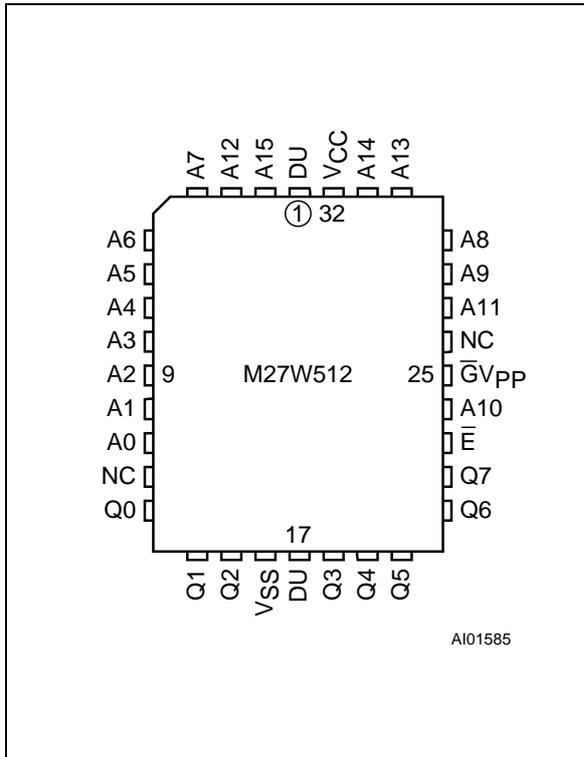
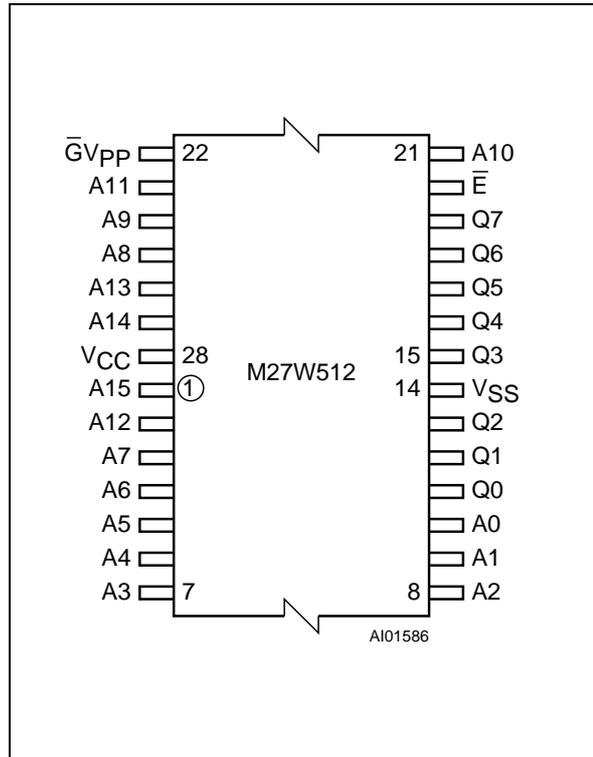


Figure 2B. TSOP Pin Connections



Warning: NC = Not Connected, DU = Don't Use

Table 2. Absolute Maximum Ratings <sup>(1)</sup>

Symbol	Parameter	Value	Unit
T <sub>A</sub>	Ambient Operating Temperature <sup>(3)</sup>	-40 to 125	°C
T <sub>BIAS</sub>	Temperature Under Bias	-50 to 125	°C
T <sub>STG</sub>	Storage Temperature	-65 to 150	°C
V <sub>IO</sub> <sup>(2)</sup>	Input or Output Voltages (except A9)	-2 to 7	V
V <sub>CC</sub>	Supply Voltage	-2 to 7	V
V <sub>A9</sub> <sup>(2)</sup>	A9 Voltage	-2 to 13.5	V
V <sub>PP</sub>	Program Supply Voltage	-2 to 14	V

- Notes:** 1. Except for the rating "Operating Temperature Range", stresses above those listed in the Table "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.
2. Minimum DC voltage on Input or Output is -0.5V with possible undershoot to -2.0V for a period less than 20ns. Maximum DC voltage on Output is V<sub>CC</sub> +0.5V with possible overshoot to V<sub>CC</sub> +2V for a period less than 20ns.
3. Depends on range.

**Table 3. Operating Modes**

Mode	$\bar{E}$	$\bar{G}V_{PP}$	A9	Q0 - Q7
Read	$V_{IL}$	$V_{IL}$	X	Data Out
Output Disable	$V_{IL}$	$V_{IH}$	X	Hi-Z
Program	$V_{IL}$ Pulse	$V_{PP}$	X	Data In
Program Inhibit	$V_{IH}$	$V_{PP}$	X	Hi-Z
Standby	$V_{IH}$	X	X	Hi-Z
Electronic Signature	$V_{IL}$	$V_{IL}$	$V_{ID}$	Codes

Note: X =  $V_{IH}$  or  $V_{IL}$ ,  $V_{ID} = 12V \pm 0.5V$

**Table 4. Electronic Signature**

Identifier	A0	Q7	Q6	Q5	Q4	Q3	Q2	Q1	Q0	Hex Data
Manufacturer's Code	$V_{IL}$	0	0	1	0	0	0	0	0	20h
Device Code	$V_{IH}$	0	0	1	1	1	1	0	1	3Dh

## DEVICE OPERATION

The modes of operations of the M27W512 are listed in the Operating Modes table. A single power supply is required in the read mode. All inputs are TTL levels except for  $\bar{G}V_{PP}$  and 12V on A9 for Electronic Signature.

### Read Mode

The M27W512 has two control functions, both of which must be logically active in order to obtain data at the outputs. Chip Enable ( $\bar{E}$ ) is the power control and should be used for device selection. Output Enable ( $\bar{G}$ ) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that the addresses are stable, the address access time ( $t_{AVQV}$ ) is equal to the delay from  $\bar{E}$  to output ( $t_{ELQV}$ ). Data is available at the output after a delay of  $t_{GLQV}$  from the falling edge of  $\bar{G}$ , assuming that  $\bar{E}$  has been low and the addresses have been stable for at least  $t_{AVQV} - t_{GLQV}$ .

### Standby Mode

The M27W512 has a standby mode which reduces the supply current from 15mA to 15 $\mu$ A with low voltage operation  $V_{CC} \leq 3.6V$ , see Read Mode DC

Characteristics table for details. The M27W512 is placed in the standby mode by applying a CMOS high signal to the  $\bar{E}$  input. When in the standby mode, the outputs are in a high impedance state, independent of the  $\bar{G}V_{PP}$  input.

### Two Line Output Control

Because EPROMs are usually used in larger memory arrays, the product features a 2 line control function which accommodates the use of multiple memory connection. The two line control function allows:

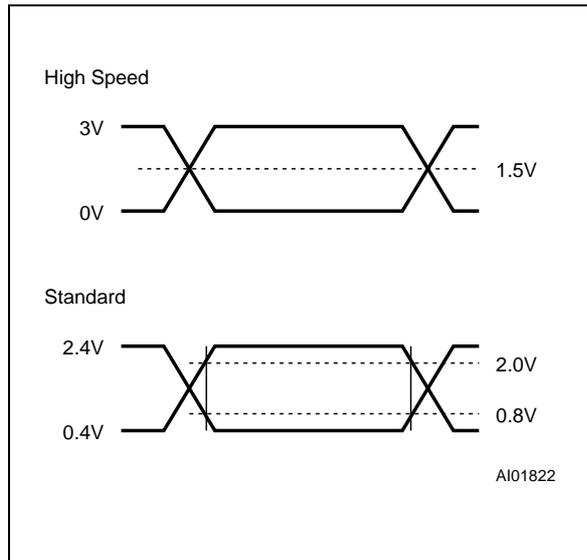
- the lowest possible memory power dissipation,
- complete assurance that output bus contention will not occur.

For the most efficient use of these two control lines,  $\bar{E}$  should be decoded and used as the primary device selecting function, while  $\bar{G}$  should be made a common connection to all devices in the array and connected to the READ line from the system control bus. This ensures that all deselected memory devices are in their low power standby mode and that the output pins are only active when data is required from a particular memory device.

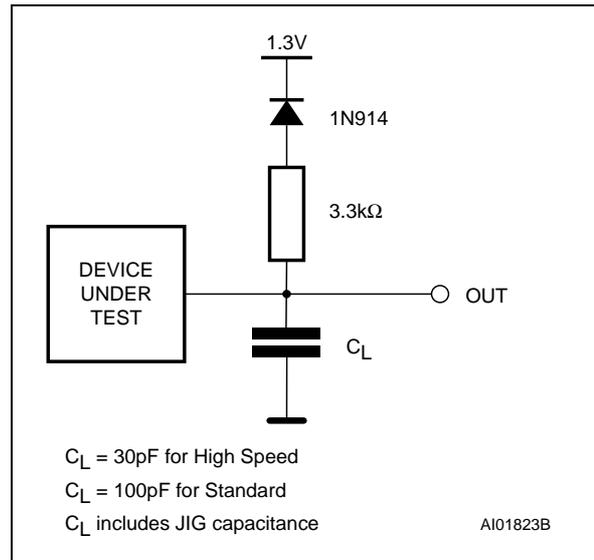
**Table 5. AC Measurement Conditions**

	High Speed	Standard
Input Rise and Fall Times	≤ 10ns	≤ 20ns
Input Pulse Voltages	0 to 3V	0.4V to 2.4V
Input and Output Timing Ref. Voltages	1.5V	0.8V and 2V

**Figure 3. AC Testing Input Output Waveform**



**Figure 4. AC Testing Load Circuit**



**Table 6. Capacitance <sup>(1)</sup> ( $T_A = 25\text{ }^\circ\text{C}$ ,  $f = 1\text{ MHz}$ )**

Symbol	Parameter	Test Condition	Min	Max	Unit
$C_{IN}$	Input Capacitance	$V_{IN} = 0V$		6	pF
$C_{OUT}$	Output Capacitance	$V_{OUT} = 0V$		12	pF

**Note.** 1. Sampled only, not 100% tested.

**System Considerations**

The power switching characteristics of Advanced CMOS EPROMs require careful decoupling of the devices. The supply current,  $I_{CC}$ , has three segments that are of interest to the system designer: the standby current level, the active current level, and transient current peaks that are produced by the falling and rising edges of  $\bar{E}$ . The magnitude of the transient current peaks is dependent on the capacitive and inductive loading of the device at the output.

The associated transient voltage peaks can be suppressed by complying with the two line output

control and by properly selected decoupling capacitors. It is recommended that a  $0.1\mu\text{F}$  ceramic capacitor be used on every device between  $V_{CC}$  and  $V_{SS}$ . This should be a high frequency capacitor of low inherent inductance and should be placed as close to the device as possible. In addition, a  $4.7\mu\text{F}$  bulk electrolytic capacitor should be used between  $V_{CC}$  and  $V_{SS}$  for every eight devices. The bulk capacitor should be located near the power supply connection point. The purpose of the bulk capacitor is to overcome the voltage drop caused by the inductive effects of PCB traces.

**Table 7. Read Mode DC Characteristics (1)**  
 ( $T_A = -40$  to  $85^\circ\text{C}$ ;  $V_{CC} = 2.7\text{V}$  to  $3.6\text{V}$ ;  $V_{PP} = V_{CC}$ )

Symbol	Parameter	Test Condition	Min	Max	Unit
$I_{LI}$	Input Leakage Current	$0\text{V} \leq V_{IN} \leq V_{CC}$		$\pm 10$	$\mu\text{A}$
$I_{LO}$	Output Leakage Current	$0\text{V} \leq V_{OUT} \leq V_{CC}$		$\pm 10$	$\mu\text{A}$
$I_{CC}$	Supply Current	$\bar{E} = V_{IL}, \bar{G} = V_{IL},$ $I_{OUT} = 0\text{mA}, f = 5\text{MHz},$ $V_{CC} \leq 3.6\text{V}$		15	mA
$I_{CC1}$	Supply Current (Standby) TTL	$\bar{E} = V_{IH}$		1	mA
$I_{CC2}$	Supply Current (Standby) CMOS	$\bar{E} > V_{CC} - 0.2\text{V},$ $V_{CC} \leq 3.6\text{V}$		15	$\mu\text{A}$
$I_{PP}$	Program Current	$V_{PP} = V_{CC}$		10	$\mu\text{A}$
$V_{IL}$	Input Low Voltage		-0.6	$0.2 V_{CC}$	V
$V_{IH}^{(2)}$	Input High Voltage		$0.7 V_{CC}$	$V_{CC} + 0.5$	V
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.1\text{mA}$		0.4	V
$V_{OH}$	Output High Voltage TTL	$I_{OH} = -1\text{mA}$	2.4		V

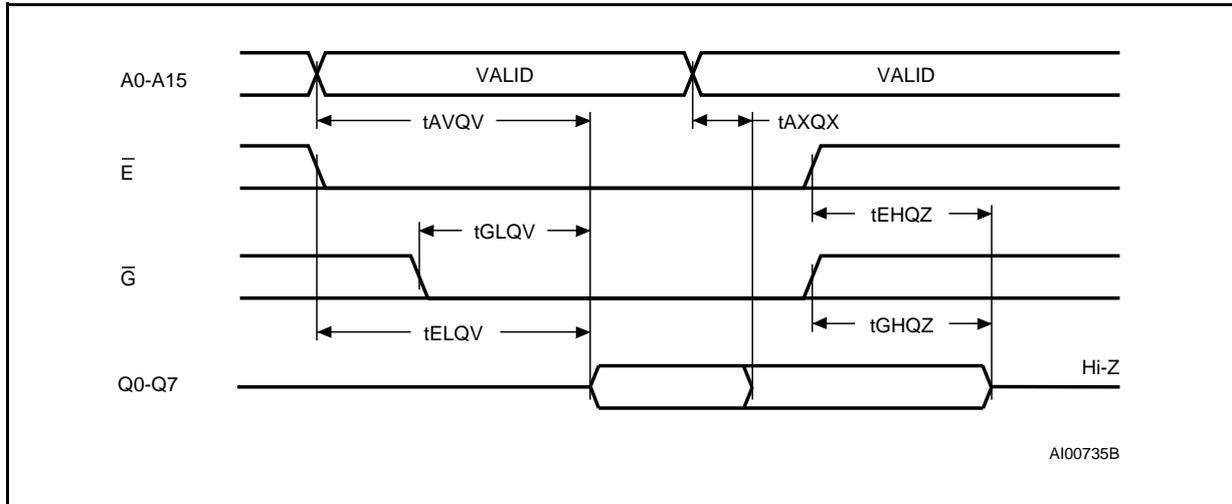
Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .  
 2. Maximum DC voltage on Output is  $V_{CC} + 0.5\text{V}$ .

**Table 8. Read Mode AC Characteristics (1)**  
 ( $T_A = -40$  to  $85^\circ\text{C}$ ;  $V_{CC} = 2.7\text{V}$  to  $3.6\text{V}$ ;  $V_{PP} = V_{CC}$ )

Symbol	Alt	Parameter	Test Condition	M27W512						Unit
				-100 <sup>(3)</sup>				-120 (-150/-200)		
				$V_{CC} = 3.0\text{V to } 3.6\text{V}$		$V_{CC} = 2.7\text{V to } 3.6\text{V}$		$V_{CC} = 2.7\text{V to } 3.6\text{V}$		
				Min	Max	Min	Max	Min	Max	
$t_{AVQV}$	$t_{ACC}$	Address Valid to Output Valid	$\bar{E} = V_{IL},$ $\bar{G} = V_{IL}$		90		100		120	ns
$t_{ELQV}$	$t_{CE}$	Chip Enable Low to Output Valid	$\bar{G} = V_{IL}$		90		100		120	ns
$t_{GLQV}$	$t_{OE}$	Output Enable Low to Output Valid	$\bar{E} = V_{IL}$		50		60		70	ns
$t_{EHQZ}^{(2)}$	$t_{DF}$	Chip Enable High to Output Hi-Z	$\bar{G} = V_{IL}$	0	50	0	60	0	70	ns
$t_{GHQZ}^{(2)}$	$t_{DF}$	Output Enable High to Output Hi-Z	$\bar{E} = V_{IL}$	0	50	0	60	0	70	ns
$t_{AXQX}$	$t_{OH}$	Address Transition to Output Transition	$\bar{E} = V_{IL},$ $\bar{G} = V_{IL}$	0		0		0		ns

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .  
 2. Sampled only, not 100% tested.  
 3. Speed obtained with High Speed AC measurement conditions.

Figure 5. Read Mode AC Waveforms



**Table 9. Programming Mode DC Characteristics <sup>(1)</sup>**  
 ( $T_A = 25\text{ }^\circ\text{C}$ ;  $V_{CC} = 6.25\text{V} \pm 0.25\text{V}$ ;  $V_{PP} = 12.75\text{V} \pm 0.25\text{V}$ )

Symbol	Parameter	Test Condition	Min	Max	Unit
$I_{LI}$	Input Leakage Current	$V_{IL} \leq V_{IN} \leq V_{IH}$		$\pm 10$	$\mu\text{A}$
$I_{CC}$	Supply Current			50	mA
$I_{PP}$	Program Current	$\bar{E} = V_{IL}$		50	mA
$V_{IL}$	Input Low Voltage		-0.3	0.8	V
$V_{IH}$	Input High Voltage		2	$V_{CC} + 0.5$	V
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.1\text{mA}$		0.4	V
$V_{OH}$	Output High Voltage TTL	$I_{OH} = -1\text{mA}$	3.6		V
$V_{ID}$	A9 Voltage		11.5	12.5	V

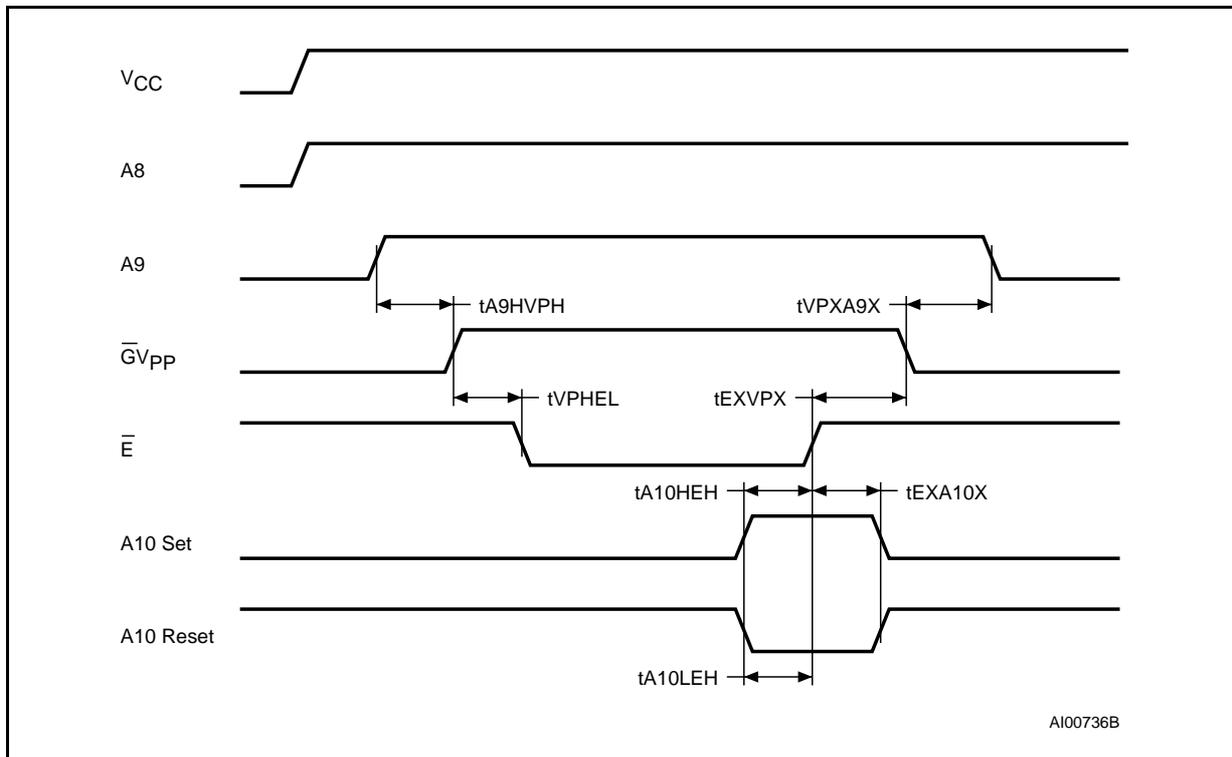
**Note:** 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

**Table 10. MARGIN MODE AC Characteristics (1)**  
 ( $T_A = 25\text{ }^\circ\text{C}$ ;  $V_{CC} = 6.25\text{V} \pm 0.25\text{V}$ ;  $V_{PP} = 12.75\text{V} \pm 0.25\text{V}$ )

Symbol	Alt	Parameter	Test Condition	Min	Max	Unit
$t_{A9HVPH}$	$t_{AS9}$	VA9 High to $V_{PP}$ High		2		$\mu\text{s}$
$t_{VPHEL}$	$t_{VPS}$	$V_{PP}$ High to Chip Enable Low		2		$\mu\text{s}$
$t_{A10HEH}$	$t_{AS10}$	VA10 High to Chip Enable High (Set)		1		$\mu\text{s}$
$t_{A10LEH}$	$t_{AS10}$	VA10 Low to Chip Enable High (Reset)		1		$\mu\text{s}$
$t_{EXA10X}$	$t_{AH10}$	Chip Enable Transition to VA10 Transition		1		$\mu\text{s}$
$t_{EXVPX}$	$t_{VPH}$	Chip Enable Transition to $V_{PP}$ Transition		2		$\mu\text{s}$
$t_{VPXA9X}$	$t_{AH9}$	$V_{PP}$ Transition to VA9 Transition		2		$\mu\text{s}$

**Note:** 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

**Figure 6. MARGIN MODE AC Waveforms**



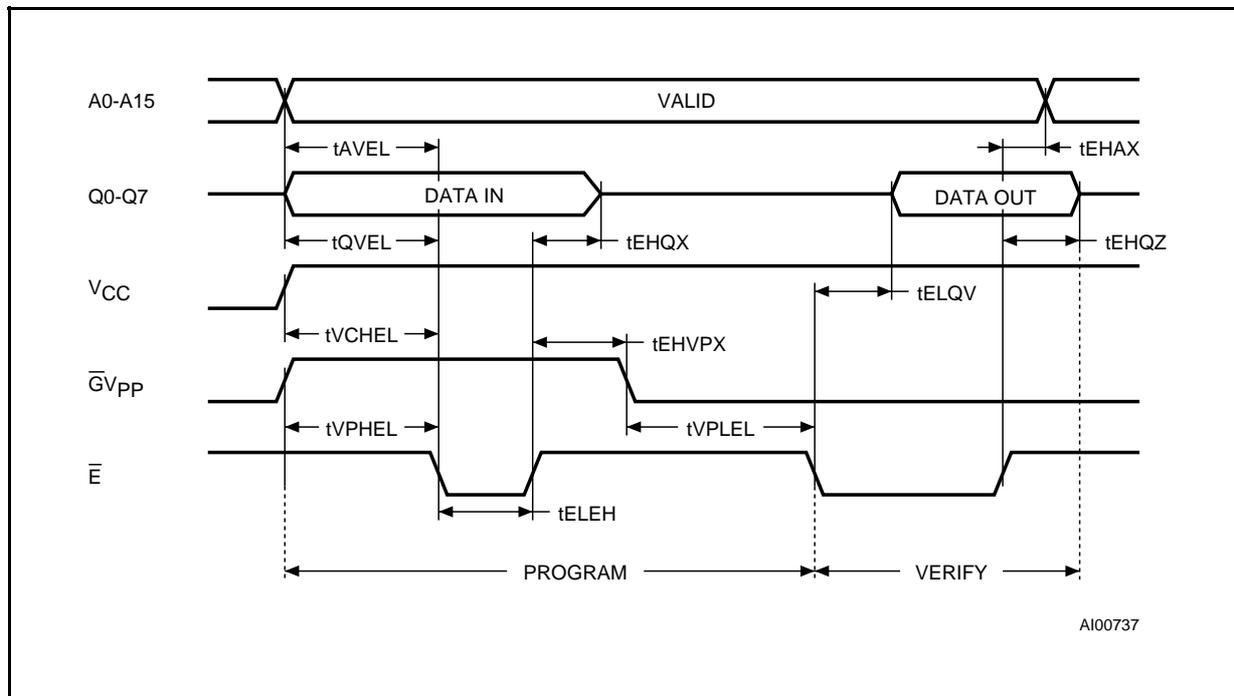
**Note:** A8 High level = 5V; A9 High level = 12V.

**Table 11. Programming Mode AC Characteristics <sup>(1)</sup>**  
 ( $T_A = 25\text{ }^\circ\text{C}$ ;  $V_{CC} = 6.25\text{V} \pm 0.25\text{V}$ ;  $V_{PP} = 12.75\text{V} \pm 0.25\text{V}$ )

Symbol	Alt	Parameter	Test Condition	Min	Max	Unit
$t_{AVEL}$	$t_{AS}$	Address Valid to Chip Enable Low		2		$\mu\text{s}$
$t_{QVEL}$	$t_{DS}$	Input Valid to Chip Enable Low		2		$\mu\text{s}$
$t_{VCHEL}$	$t_{VCS}$	$V_{CC}$ High to Chip Enable Low		2		$\mu\text{s}$
$t_{VPHEL}$	$t_{OES}$	$V_{PP}$ High to Chip Enable Low		2		$\mu\text{s}$
$t_{VPLVPH}$	$t_{PRT}$	$V_{PP}$ Rise Time		50		ns
$t_{ELEH}$	$t_{PW}$	Chip Enable Program Pulse Width (Initial)		95	105	$\mu\text{s}$
$t_{EHQX}$	$t_{DH}$	Chip Enable High to Input Transition		2		$\mu\text{s}$
$t_{EHVPX}$	$t_{OEH}$	Chip Enable High to $V_{PP}$ Transition		2		$\mu\text{s}$
$t_{VPLEL}$	$t_{VR}$	$V_{PP}$ Low to Chip Enable Low		2		$\mu\text{s}$
$t_{ELQV}$	$t_{DV}$	Chip Enable Low to Output Valid			1	$\mu\text{s}$
$t_{EHQZ}^{(2)}$	$t_{DFP}$	Chip Enable High to Output Hi-Z		0	130	ns
$t_{EHAX}$	$t_{AH}$	Chip Enable High to Address Transition		0		ns

**Notes:** 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .  
 2. Sampled only, not 100% tested.

**Figure 7. Programming and Verify Modes AC Waveforms**



## Programming

The M27W512 has been designed to be fully compatible with the M27C512 and has the same electronic signature. As a result the M27W512 can be programmed as the M27C512 on the same programming equipment applying 12.75V on  $V_{PP}$  and 6.25V on  $V_{CC}$ . The M27W512 can use PRESTO IIB Programming Algorithm that drastically reduces the programming time. Nevertheless to achieve compatibility with all programming equipments, PRESTO II Programming Algorithm can be used as well.

When delivered, all bits of the M27W512 are in the '1' state. Data is introduced by selectively programming '0's into the desired bit locations. Although only '0's will be programmed, both '1's and '0's can be present in the data word. The M27W512 is in the programming mode when  $V_{PP}$  input is at 12.75V and  $\bar{E}$  is pulsed to  $V_{IL}$ . The data to be programmed is applied to 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL.  $V_{CC}$  is specified to be  $6.25V \pm 0.25V$ .

### PRESTO IIB Programming Algorithm

PRESTO IIB Programming Algorithm allows the whole array to be programmed with a guaranteed margin, in a typical time of 6.5 seconds. This can be achieved with STMicroelectronics M27W512 due to several design innovations described in the M27W512 datasheet to improve programming efficiency and to provide adequate margin for reliability. Before starting the programming the internal MARGIN MODE circuit is set in order to guarantee that each cell is programmed with enough margin. Then a sequence of 100 $\mu$ s program pulses is applied to each byte until a correct verify occurs. No overprogram pulses are applied since the verify in MARGIN MODE at  $V_{CC}$  much higher than 3.6V, provides the necessary margin.

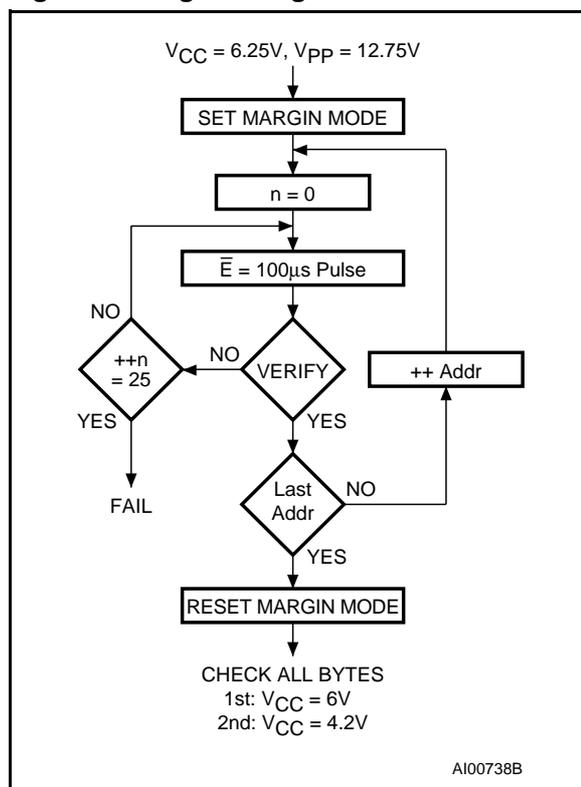
### Program Inhibit

Programming of multiple M27W512s in parallel with different data is also easily accomplished. Except for  $\bar{E}$ , all like inputs including  $\bar{G}V_{PP}$  of the parallel M27W512 may be common. A TTL low level pulse applied to a M27W512's  $\bar{E}$  input, with  $V_{PP}$  at 12.75V, will program that M27W512. A high level  $\bar{E}$  input inhibits the other M27W512s from being programmed.

### Program Verify

A verify (read) should be performed on the programmed bits to determine that they were correctly programmed. The verify is accomplished with  $\bar{G}$  at  $V_{IL}$ . Data should be verified with  $t_{ELQV}$  after the falling edge of  $\bar{E}$ .

Figure 8. Programming Flowchart



## On-Board Programming

The M27W512 can be directly programmed in the application circuit. See the relevant Application Note AN620.

## Electronic Signature

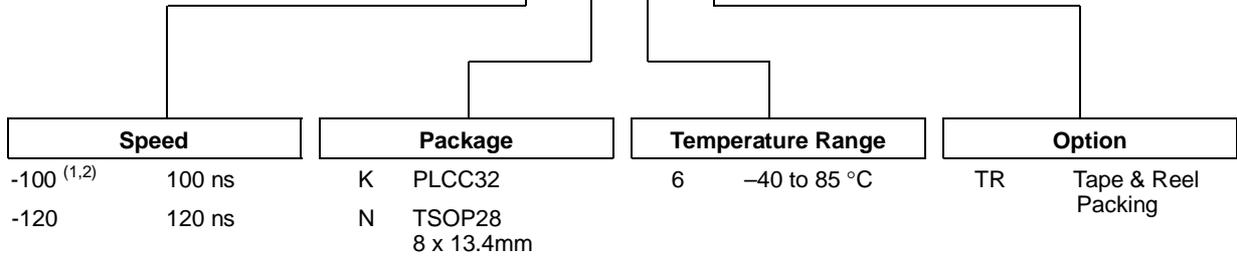
The Electronic Signature (ES) mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment to automatically match the device to be programmed with its corresponding programming algorithm. The ES mode is functional in the  $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$  ambient temperature range that is required when programming the M27W512. To activate the ES mode, the programming equipment must force 11.5V to 12.5V on address line A9 of the M27W512. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from  $V_{IL}$  to  $V_{IH}$ . All other address lines must be held at  $V_{IL}$  during Electronic Signature mode.

Byte 0 ( $A0=V_{IL}$ ) represents the manufacturer code and byte 1 ( $A0=V_{IH}$ ) the device identifier code. For the STMicroelectronics M27W512, these two identifier bytes are given in Table 4 and can be read-out on outputs Q0 to Q7.

Note that the M27W512 and M27C512 have the same identifier byte.

**ORDERING INFORMATION SCHEME**

Example: M27W512 -100 K 6 TR



Speed		Package		Temperature Range		Option	
-100 <sup>(1,2)</sup>	100 ns	K	PLCC32	6	-40 to 85 °C	TR	Tape & Reel Packing
-120	120 ns	N	TSOP28 8 x 13.4mm				

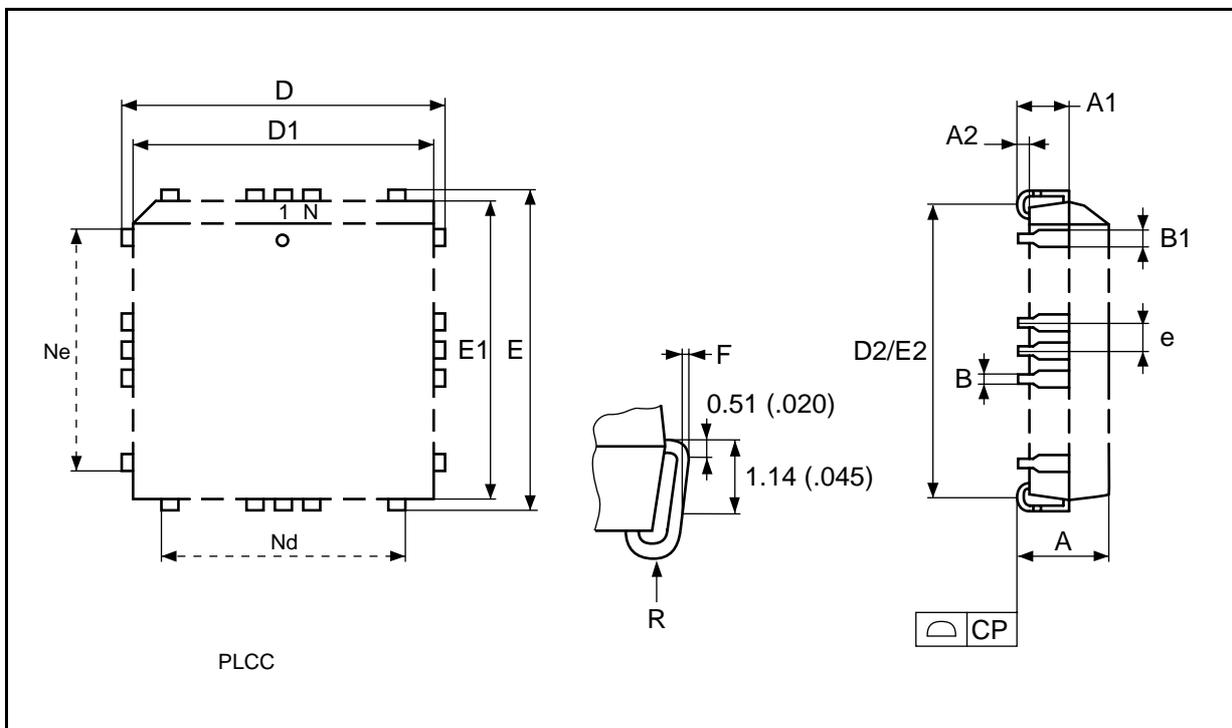
<b>NOT FOR NEW DESIGN</b> <sup>(3)</sup>	
-150	150 ns
-200	200 ns

- Notes:**
1. High Speed, see AC Characteristics section for further information.
  2. This speed also guarantees 90ns access time at V<sub>CC</sub> = 3.0V to 3.6V.
  3. These speeds are replaced by the 120ns.

For a list of available options (Speed, Package etc...) or for further information on any aspect of this device, please contact the STMicroelectronics Sales Office nearest to you.

### PLCC32 - 32 lead Plastic Leaded Chip Carrier, rectangular

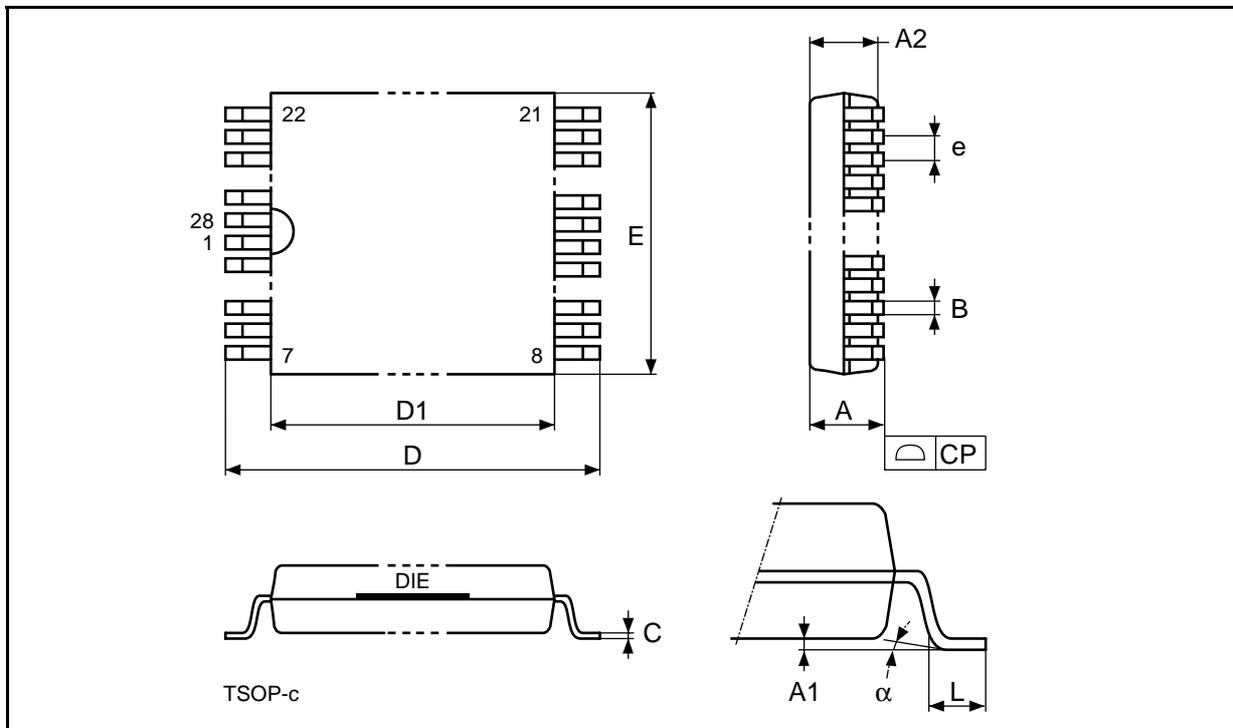
Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		2.54	3.56		0.100	0.140
A1		1.52	2.41		0.060	0.095
A2		–	0.38		–	0.015
B		0.33	0.53		0.013	0.021
B1		0.66	0.81		0.026	0.032
D		12.32	12.57		0.485	0.495
D1		11.35	11.56		0.447	0.455
D2		9.91	10.92		0.390	0.430
E		14.86	15.11		0.585	0.595
E1		13.89	14.10		0.547	0.555
E2		12.45	13.46		0.490	0.530
e	1.27	–	–	0.050	–	–
F		0.00	0.25		0.000	0.010
R	0.89	–	–	0.035	–	–
N		32			32	
Nd		7			7	
Ne		9			9	
CP			0.10			0.004



Drawing is not to scale

**TSOP28 - 28 lead Plastic Thin Small Outline, 8 x 13.4mm**

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A			1.25			0.049
A1			0.20			0.008
A2		0.95	1.15		0.037	0.045
B		0.17	0.27		0.007	0.011
C		0.10	0.21		0.004	0.008
D		13.20	13.60		0.520	0.535
D1		11.70	11.90		0.461	0.469
E		7.90	8.10		0.311	0.319
e	0.55	–	–	0.022	–	–
L		0.50	0.70		0.020	0.028
$\alpha$		0°	5°		0°	5°
N	28			28		
CP			0.10			0.004



Drawing is not to scale

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